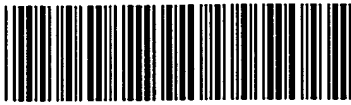


**Search Notes**

Application/Control No.

10/783,172

Examiner

Evan Dzierzynski

Applicant(s)/Patent under  
Reexamination

MAYER ET AL.

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
362	547	7/21/2005	EPD
362	548	7/21/2005	EPD
362	549	7/21/2005	EPD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search strategy advice from Peggy Niels	7/21/2005	EPD
Subclass and word search in East, see attachment	7/21/2005	EPD